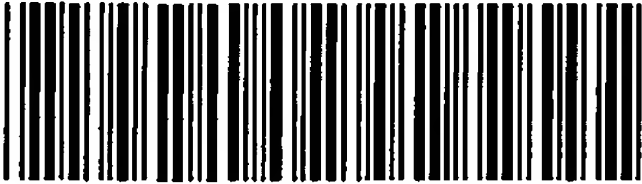


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/621,074	LAM ET AL.	
	Examiner	Art Unit	
	Sun J. Lin	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	1	11/10/2005	JSL
716	16	11/10/2005	JSL
716	17	11/10/2005	JSL
375	354	11/10/2005	JSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	1	11/10/2005	JSL
716	16	11/10/2005	JSL
716	17	11/10/2005	JSL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	11/10/2005	JSL
IEEE	11/11/2005	JSL